Optical Spectrum Analyzer

Fiber-optic test, measurement and monitoring instruments OPTICAL SPECTRUM ANALYZER



Modular integration (IQ-200 Optical Test System) High-performance technical specifications Telecom range: 1250 to 1650 nm

GPIB interface

NPUT



Measurement Solutions with Optimized Dynamic Range

Designed to improve your productivity, EXFO's new modular IQ-5240 Optical Spectrum Analyzer delivers high-quality signal-to-noise ratio (SNR) measurements for WDM test applications. In narrowly spaced systems, high-power peaks can plague secondary wavelengths generated by non-linear effects such as four-wave mixing and self-phase modulation. If your analyzer lacks dynamic range, it can misread new generated wavelengths or amplified spontaneous emission (ASE) between peaks. The IQ-5240 OSA design meets most requirements for systems with 50 GHz spacing since it delivers an optical rejection ratio of 40 dBc at 25 GHz (0.2 nm) from a high-power, spectrally narrow peak.



Top-of-the-Line Wavelength Resolution and Accuracy

The IQ-5240 is a double-pass Littman-Metcalf monochromator that provides premium filter resolution bandwidth (65 pm in C-band) with a steep, high-rejection shape. The OSA grating rotates on a gearless DC motor. A high-resolution encoder locates and controls the filter position at all times. Linearity and stability are guaranteed due to an innovative optical design limiting misalignment and inaccuracies.

Fast Scans at High Resolution

Many production managers and test engineers believe that wide-range, high-resolution power distribution measurements require a long scanning period. But with the IQ-5240 OSA, you can bypass that wait. For example, the new OSA can sample and analyze 5000 data points over a 50 nm span with 10 pm resolution, in less than a second. It can also collect up to 10001 data points with a maximum resolution of 5 pm.

Excellent Power Measurement Specifications

You benefit from the innovative optical design (patent pending) of the IQ-5240 OSA in more ways than one. We've combined small size with high resolution to deliver well-packaged functionality in the lab and on the production floor—all without compromising on polarization-dependent sensitivity. High-performance PDL reduction offers a low 0.07 dB change in loss over all possible states of polarization, resulting in repeatable and reliable polarized signal spectrum measurement. The rugged, single-grating (double-pass) approach provides stable alignment between the monochromator's input fiber and output slit.



IQ-200 Platform: Expanding Test Options

The IQ-5240 OSA is part of EXFO's flexible IQ-200 Optical Test System, an integrated work and test station. Combine the IQ-5240 OSA with LEDs, ASE sources, power meters, or wavelength meters to streamline your lab and production testing. Even better, you aren't limited to one or two instruments—they can all be integrated into the IQ-200 Optical Test System.

10-5240

Key Features

Automated Analysis



WDM signals: central wavelength, power and SNR for each peak

Easy Trace Management

The application window is a visual menu where operations can be applied to two or more traces.

Total Power Measurement

Choose between peak or integrated (between user-defined limits) definitions. Four traces can be acquired and accessed for processing and analysis. A new incoming trace can be identified as a drift curve (power and central wavelength variation over time) or a spectral distribution curve (wavelength spectrum at a particular time).

EDFA gain and parameters

Set your own parameters for drift trace acquisitions. Parameters include acquisition time period and sampling rate. Performing drift analysis on more than 100 channels is no longer an arduous task.

Specifications¹

| Wavelength | | |
|--|------------------|--------------------------|
| Range (nm) | | 1250 to 1650 |
| Adjustable span (nm) | | Full to 1 |
| Maximum data points resolution (pm) | | 5 |
| Resolution BW ² (pm) | | 65 |
| Uncertainty ³ (pm) | | <u>±</u> 50 |
| Linearity⁴ (pm) | | ±10 |
| Repeatability (pm) 1 min | | <5 |
| Power level | | |
| Range⁵ (dBm) | | -75 to +15 |
| Uncertainty ⁶ (dB) | | ±0.4 |
| Linearity (dB) | Over 20 dB range | ±0.1 |
| | Over 40 dB range | ±0.2 |
| Uniformity in C-band (dB) | Typical | ±0.1 |
| Repeatability (dB) 1 min | | ±0.05 |
| Polarization sensitivity ⁴ (dB) | Typical | ±0.1 |
| | Maximum | <u>+</u> 0.15 |
| Dynamic range (C-band) | | |
| @ 1 nm from peak (dBc) | | >50 |
| @ 0.4 nm from peak (dBc) | | >45 |
| @ 0.2 nm from peak (dBc) | | >35 |
| Sweep | | |
| Sweep time (s) ⁷ | | <1 |
| Maximum number of data points ⁸ | | 10001 |
| Data storage format | | ASCII, .OSW ⁹ |
| ORL | | |
| Return loss (dB) | | >35 |
| | Typical | >45 |
| | | |

NOTES

Specifications valid at 23 ±2°C and with FC/UPC connector after warmup. 1.

Characteristic value for C-band. Factory-calibrated within C-and L-bands. 2. Signal-to-noise ratio can be either directly measured with actual RBW or calculated with a 0.1 nm RBW.

Within C-and L-bands after external calibration. 3.

Within C-and L-bands. 4.

5. Low level specification requires averaging. High level valid for single peak.

At -10 dBm at calibration wavelengths (1310 and 1550 nm). 6. 7.

Real-time, 35 nm span, 5000 data points of raw data within IQ-200 OTS.

Range-dependent. 8.

This is an EXFO file format allowing for data analysis and reporting using the 9 same application software than for data acquisition.



Drift analysis: measures, displays, and reports time-varying peak signal power and wavelength

General Specifications

| Dimensions (with IQ-200 OTS)(H x W x D) | 14.5 x 36 x 30.5 cm/5 ^{3/4} x 14 ^{1/4} x 12 in. | |
|---|---|--|
| Weight (kg/lb) (with IQ-203 OTS) | 8/17.5 | |
| Operating temperature (°C) | 10 to 40 | |
| Storage temperature (°C) | -20 to +50 | |
| Humidity (%) (non-condensing) | <95 | |
| | | |

Remote Control

SCPI commands

Instruments Drivers

GPIB, RS-232

Ordering Information

| Optical Spectrum Analyzer IQ-5240-XX I | | | | | |
|--|---|--|--|------------------------------|--|
| EI = EXFO UPC Universal Interface EA = EXFO APC Universal Interface | | | Connector adapter The fixed base-plate (El or EA) must be ordered with a removable universal connector adapter (EUI-XX). Please specify one EUI from the following list: EUI-89 = FC EUI-91 = SC EUI-95 = E-2000 | | |
| CORPORATE HEADQUARTERS | 465 Godin Avenue | Vanier (Quebec) G1M 3G7 CANADA Tel.: (418) 683-0211 • Fax: (418) 683-2170 | | | |
| EXFO AMERICA | 1201 Richardson Drive, Suite 260 | Richardson TX, 75080, USA Tel.: 1 800 663-3936 • Fax: (972) 907-2297 | 1 | EVEA | |
| EXFO EUROPE | O EUROPE Centre d'Affaires Les Metz Jouy-en-Josas, FRANCE 100, rue Albert Calmette, 78353 Tel.: +33.1.34.63.00.20 · Fax: +33.1.34.65.90.93 | | 0.93 | | |
| EXFO ASIA PACIFIC | 151 Chin Swee Road #3-29, Manhattan House | SINGAPORE 169876 Tel.: +65 333 8241 • Fax: +65 333 8242 | | | |
| TOLL FREE | (USA and Canada) | 1 800 663-3936 | | www.exfo.com • info@exfo.com | |
| | | | | | |

EXFO is certified ISO 9001 and attests to the quality of its products. These products are accompanied by a 24-month warranty and an excellent after-sales support service. This device complies with Part 15 of the FCC Rules. Operation is subject to the following two conditions: (1) this device may not cause harmful interference, and (2) this device must accept any interference received, including interference that may cause undesired operation.

EXFO has made every effort to ensure that the information contained in this brochure is accurate. However, we accept no responsibility for any errors or omissions, and we reserve the right to modify design, characteristics and products at any time without obligation.

Contact EXFO for prices and availability or to obtain the phone number of your local EXFO distributor.

SPIQ-5240.2AN 01/03 © 2001 EXFO Electro-Optical Engineering Inc. All rights reserved.

